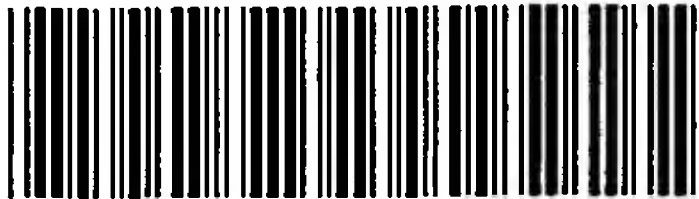


<div>Search Notes</div> <div></div>	Application/Control No.	Applicant(s)/Patent under Reexamination	
	10/711,470	SHEI ET AL.	
	Examiner	Art Unit	
	Thien T. Mai	2876	

SEARCHED			
Class	Subclass	Date	Examiner
438	612	10/26/2005	TM
	613		
	106		

INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner

SEARCH NOTES (INCLUDING SEARCH STRATEGY)		
	DATE	EXMR
EAST	10/26/2005	TM